Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/692,894	HWANG ET AL.	
Examiner	Art Unit	
Emmanuel Bayard	2611	

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Class	Subclass	Date	Examiner
375	259	12/22/2006	EB
375	260	12/22/2006	EB
375	299	12/22/2006	EB
375	308	12/22/2006	EB
375	316	12/22/2006	EB
375	337	12/22/2006	EB
375	341	12/22/2006	EB
375	347	12/22/2006	EB

INT	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
East		12/22/2006	EB		
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